
Identification cards — Physical characteristics

Cartes d'identification — Caractéristiques physiques

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Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work.

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This document was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

This fourth edition cancels and replaces the third edition (ISO/IEC 7810:2003), which has been technically revised. It also incorporates the Amendments ISO/IEC 7810:2003/Amd.1:2009 and ISO/IEC 7810:2003/Amd.2:2012.

The main changes compared to the previous edition are as follows:

- the test method and criteria for opacity has changed; previously the test method used a spectrophotometer and criteria included both visible and IR light; the present method uses 2 frequencies of only IR light and a reference material to establish compliance;
- criteria for cards containing certain types of IC's has been added (formerly these were in the specific IC card standards but as the same requirement applies to many types of IC cards they have been placed in this document);
- the heat deflection test (formerly Annex A) has been placed in ISO/IEC 10373-1;
- the clause on light exposure has additional explanation;
- the overall size tolerance of the ID-1 size returned card has changed (5.2);
- patch layer peel strength has been added and is lower than other values (8.7);
- address for availability of optical reference media has changed.

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